



Advanced Sensing Technology for Structural Health Monitoring

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Message from the Guest Editors

Dear Colleagues,

Structural health monitoring (SHM) aims to develop automated systems for the continuous monitoring, inspection, and damage detection of structures with minimum labor involvement. However, there are several challenges in creating such advanced sensing technologies for monitoring various physical or chemical parameters related to the health and durable service life of structures. Therefore, this Special Issue aims to present new ideas and experimental results in the field of advanced sensing technology theory which might contribute to its practical application.

This Special Issue will publish high-quality original research papers in the following relevant and interrelated fields, including, but not limited to, detection diagnosis, damage detection and imaging, fiber optic sensors, piezoelectric sensors, magnetostrictive sensors, strain sensors, pressure sensors, microwave sensors, and instrumentation and measurement. Non-destructive testing is also another topic of interest.





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Message from the Editor-in-Chief

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